



Course Number E7086A+24D or 24A Scheduled, Dedicated

Agilent V1200, V1300, and V3300 Basic Operating and Programming

Overview

Learn to develop and debug software for the V1200, V1300, and V3300 semiconductor measurement systems

Course Overview

This course teaches you specifics of the Agilent Technologies V1200, V1300, and V3300 test systems. Lectures focus on test program development and debug and presents pertinent details of the tester hardware and operating system software.

Daily hands-on laboratory work includes writing and debugging your own test program code in the Windows NT VK Test Station software environment.

What You Will Learn

At the end of this five-day class, you will:

- Know the fundamental purpose, architecture, and capabilities of V1200, V1300, and V3300 test systems
- Be competent to operate these test systems
- Be competent to read, debug, and write test programs for these test systems.

Specifications

Course Type

User/Application training

Audience

VK test program developers and test engineers who will be developing test programs on V1200, V1300, and V3300 systems.

Prerequisites

None

Course Length

5 days

Course Format

40% lecture and 60% hands-on lab and exercises

Delivery Method

Scheduled (at Agilent training locations) or

Dedicated (at customer site)

To save you time and travel, many Agilent courses can be delivered at your site. Agilent can provide required equipment, or save money by furnishing your own.

Detailed Course Agenda

Monday

- Class Introduction
- VK Test Systems Introduction
- Hardware Architecture Overview
- Test Program Fundamentals
- Programmable Power Supplies and Voltage References
- DUT Programmable Power Supply Channels
- Overview of Parametric Measurement Unit (PMU)
- Connecting PMU to DUT PPS Channels
- Overview of ADC
- Overview of Pin Electronics (PE) Channels
- PE COMPAT Modes
- Connecting PMU to PE Channels
- Example Parametric Tests



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Tuesday

- Software Architecture Overview
- Plan and Configuration Files
- Test Program Overview
- SHELL2.C
- Test Program Compilers
- Basic System Operation
- The Use of Selected VOS Terminal Commands
- Lab Project I

Wednesday

- Pin Electronics Drivers
- Pin Electronics Comparators
- Pattern Generator
- Source Code File Structure
- Source Code Syntax
- Cycle Times
- Channel Formatting
- VHH Control
- PEL Level Inversion
- Vector Sequencing
- A, B, and C Counters
- Vector Load Field
- More VOS Terminal Commands
- Lab Project II

Thursday

- More Pattern Generator
- PMU Strokes
- I/O Writes and I/O Reads
- APG Mode Operation
- Address and Data Generation
- Still More VOS Terminal Commands
- Lab Project III

Friday

- Buffer Memory
- Error Catch RAM
- A few more VOS Terminal Commands
- Wrap-Up
- Lab Project IV

For the latest information on class schedules and locations, visit our website:
www.agilent.com/find/tmeducation

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